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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	1024
Number of Logic Elements/Cells	2432
Total RAM Bits	32768
Number of I/O	256
Number of Gates	28000
Voltage - Supply	3V ~ 3.6V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	304-BFQFP Exposed Pad
Supplier Device Package	304-PQFP (40x40)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc4028xl-3hq304c

Detailed Functional Description

XC4000 Series devices achieve high speed through advanced semiconductor technology and improved architecture. The XC4000E and XC4000X support system clock rates of up to 80 MHz and internal performance in excess of 150 MHz. Compared to older Xilinx FPGA families, XC4000 Series devices are more powerful. They offer on-chip edge-triggered and dual-port RAM, clock enables on I/O flip-flops, and wide-input decoders. They are more versatile in many applications, especially those involving RAM. Design cycles are faster due to a combination of increased routing resources and more sophisticated software.

Basic Building Blocks

Xilinx user-programmable gate arrays include two major configurable elements: configurable logic blocks (CLBs) and input/output blocks (IOBs).

- CLBs provide the functional elements for constructing the user's logic.
- IOBs provide the interface between the package pins and internal signal lines.

Three other types of circuits are also available:

- 3-State buffers (TBUFs) driving horizontal longlines are associated with each CLB.
- Wide edge decoders are available around the periphery of each device.
- An on-chip oscillator is provided.

Programmable interconnect resources provide routing paths to connect the inputs and outputs of these configurable elements to the appropriate networks.

The functionality of each circuit block is customized during configuration by programming internal static memory cells. The values stored in these memory cells determine the logic functions and interconnections implemented in the FPGA. Each of these available circuits is described in this section.

Configurable Logic Blocks (CLBs)

Configurable Logic Blocks implement most of the logic in an FPGA. The principal CLB elements are shown in **Figure 1**. Two 4-input function generators (F and G) offer unrestricted versatility. Most combinatorial logic functions need four or fewer inputs. However, a third function generator (H) is provided. The H function generator has three inputs. Either zero, one, or two of these inputs can be the outputs of F and G; the other input(s) are from outside the CLB. The CLB can, therefore, implement certain functions of up to nine variables, like parity check or expandable-identity comparison of two sets of four inputs.

Each CLB contains two storage elements that can be used to store the function generator outputs. However, the storage elements and function generators can also be used independently. These storage elements can be configured as flip-flops in both XC4000E and XC4000X devices; in the XC4000X they can optionally be configured as latches. DIN can be used as a direct input to either of the two storage elements. H1 can drive the other through the H function generator. Function generator outputs can also drive two outputs independent of the storage element outputs. This versatility increases logic capacity and simplifies routing.

Thirteen CLB inputs and four CLB outputs provide access to the function generators and storage elements. These inputs and outputs connect to the programmable interconnect resources outside the block.

Function Generators

Four independent inputs are provided to each of two function generators (F1 - F4 and G1 - G4). These function generators, with outputs labeled F' and G', are each capable of implementing any arbitrarily defined Boolean function of four inputs. The function generators are implemented as memory look-up tables. The propagation delay is therefore independent of the function implemented.

A third function generator, labeled H', can implement any Boolean function of its three inputs. Two of these inputs can optionally be the F' and G' functional generator outputs. Alternatively, one or both of these inputs can come from outside the CLB (H2, H0). The third input must come from outside the block (H1).

Signals from the function generators can exit the CLB on two outputs. F' or H' can be connected to the X output. G' or H' can be connected to the Y output.

A CLB can be used to implement any of the following functions:

- any function of up to four variables, plus any second function of up to four unrelated variables, plus any third function of up to three unrelated variables¹
- any single function of five variables
- any function of four variables together with some functions of six variables
- some functions of up to nine variables.

Implementing wide functions in a single block reduces both the number of blocks required and the delay in the signal path, achieving both increased capacity and speed.

The versatility of the CLB function generators significantly improves system speed. In addition, the design-software tools can deal with each function generator independently. This flexibility improves cell usage.

1. When three separate functions are generated, one of the function outputs must be captured in a flip-flop internal to the CLB. Only two unregistered function generator outputs are available from the CLB.

Set/Reset

An asynchronous storage element input (SR) can be configured as either set or reset. This configuration option determines the state in which each flip-flop becomes operational after configuration. It also determines the effect of a Global Set/Reset pulse during normal operation, and the effect of a pulse on the SR pin of the CLB. All three set/reset functions for any single flip-flop are controlled by the same configuration data bit.

The set/reset state can be independently specified for each flip-flop. This input can also be independently disabled for either flip-flop.

The set/reset state is specified by using the INIT attribute, or by placing the appropriate set or reset flip-flop library symbol.

SR is active High. It is not invertible within the CLB.

Global Set/Reset

A separate Global Set/Reset line (not shown in Figure 1) sets or clears each storage element during power-up, re-configuration, or when a dedicated Reset net is driven active. This global net (GSR) does not compete with other routing resources; it uses a dedicated distribution network.

Each flip-flop is configured as either globally set or reset in the same way that the local set/reset (SR) is specified. Therefore, if a flip-flop is set by SR, it is also set by GSR. Similarly, a reset flip-flop is reset by both SR and GSR.



Figure 2: Schematic Symbols for Global Set/Reset

GSR can be driven from any user-programmable pin as a global reset input. To use this global net, place an input pad and input buffer in the schematic or HDL code, driving the GSR pin of the STARTUP symbol. (See Figure 2.) A specific pin location can be assigned to this input using a LOC attribute or property, just as with any other user-programmable pad. An inverter can optionally be inserted after the input buffer to invert the sense of the Global Set/Reset signal.

Alternatively, GSR can be driven from any internal node.

Data Inputs and Outputs

The source of a storage element data input is programmable. It is driven by any of the functions F', G', and H', or by the Direct In (DIN) block input. The flip-flops or latches drive the XQ and YQ CLB outputs.

Two fast feed-through paths are available, as shown in Figure 1. A two-to-one multiplexer on each of the XQ and YQ outputs selects between a storage element output and any of the control inputs. This bypass is sometimes used by the automated router to repower internal signals.

Control Signals

Multiplexers in the CLB map the four control inputs (C1 - C4 in Figure 1) into the four internal control signals (H1, DIN/H2, SR/H0, and EC). Any of these inputs can drive any of the four internal control signals.

When the logic function is enabled, the four inputs are:

- EC — Enable Clock
- SR/H0 — Asynchronous Set/Reset or H function generator Input 0
- DIN/H2 — Direct In or H function generator Input 2
- H1 — H function generator Input 1.

When the memory function is enabled, the four inputs are:

- EC — Enable Clock
- WE — Write Enable
- D0 — Data Input to F and/or G function generator
- D1 — Data input to G function generator (16x1 and 16x2 modes) or 5th Address bit (32x1 mode).

Using FPGA Flip-Flops and Latches

The abundance of flip-flops in the XC4000 Series invites pipelined designs. This is a powerful way of increasing performance by breaking the function into smaller subfunctions and executing them in parallel, passing on the results through pipeline flip-flops. This method should be seriously considered wherever throughput is more important than latency.

To include a CLB flip-flop, place the appropriate library symbol. For example, FDCE is a D-type flip-flop with clock enable and asynchronous clear. The corresponding latch symbol (for the XC4000X only) is called LDCE.

In XC4000 Series devices, the flip flops can be used as registers or shift registers without blocking the function generators from performing a different, perhaps unrelated task. This ability increases the functional capacity of the devices.

The CLB setup time is specified between the function generator inputs and the clock input K. Therefore, the specified CLB flip-flop setup time includes the delay through the function generator.

Using Function Generators as RAM

Optional modes for each CLB make the memory look-up tables in the F' and G' function generators usable as an array of Read/Write memory cells. Available modes are level-sensitive (similar to the XC4000/A/H families), edge-triggered, and dual-port edge-triggered. Depending on the selected mode, a single CLB can be configured as either a 16x2, 32x1, or 16x1 bit array.

Dual-Port Edge-Triggered Mode

In dual-port mode, both the F and G function generators are used to create a single 16x1 RAM array with one write port and two read ports. The resulting RAM array can be read and written simultaneously at two independent addresses. Simultaneous read and write operations at the same address are also supported.

Dual-port mode always has edge-triggered write timing, as shown in [Figure 3](#).

[Figure 6](#) shows a simple model of an XC4000 Series CLB configured as dual-port RAM. One address port, labeled A[3:0], supplies both the read and write address for the F function generator. This function generator behaves the same as a 16x1 single-port edge-triggered RAM array. The RAM output, Single Port Out (SPO), appears at the F function generator output. SPO, therefore, reflects the data at address A[3:0].

The other address port, labeled DPRA[3:0] for Dual Port Read Address, supplies the read address for the G function generator. The write address for the G function generator, however, comes from the address A[3:0]. The output from this 16x1 RAM array, Dual Port Out (DPO), appears at the G function generator output. DPO, therefore, reflects the data at address DPRA[3:0].

Therefore, by using A[3:0] for the write address and DPRA[3:0] for the read address, and reading only the DPO output, a FIFO that can read and write simultaneously is easily generated. Simultaneous access doubles the effective throughput of the FIFO.

The relationships between CLB pins and RAM inputs and outputs for dual-port, edge-triggered mode are shown in [Table 6](#). See [Figure 7 on page 16](#) for a block diagram of a CLB configured in this mode.



Figure 6: XC4000 Series Dual-Port RAM, Simple Model

Table 6: Dual-Port Edge-Triggered RAM Signals

RAM Signal	CLB Pin	Function
D	D0	Data In
A[3:0]	F1-F4	Read Address for F, Write Address for F and G
DPRA[3:0]	G1-G4	Read Address for G
WE	WE	Write Enable
WCLK	K	Clock
SPO	F'	Single Port Out (addressed by A[3:0])
DPO	G'	Dual Port Out (addressed by DPRA[3:0])

Note: The pulse following the active edge of WCLK (T_{WPS} in [Figure 3](#)) must be less than one millisecond wide. For most applications, this requirement is not overly restrictive; however, it must not be forgotten. Stopping WCLK at this point in the write cycle could result in excessive current and even damage to the larger devices if many CLBs are configured as edge-triggered RAM.

Single-Port Level-Sensitive Timing Mode

Note: Edge-triggered mode is recommended for all new designs. Level-sensitive mode, also called asynchronous mode, is still supported for XC4000 Series backward-compatibility with the XC4000 family.

Level-sensitive RAM timing is simple in concept but can be complicated in execution. Data and address signals are presented, then a positive pulse on the write enable pin (WE) performs a write into the RAM at the designated address. As indicated by the “level-sensitive” label, this RAM acts like a latch. During the WE High pulse, changing the data lines results in new data written to the old address. Changing the address lines while WE is High results in spurious data written to the new address—and possibly at other addresses as well, as the address lines inevitably do not all change simultaneously.

The user must generate a carefully timed WE signal. The delay on the WE signal and the address lines must be carefully verified to ensure that WE does not become active until after the address lines have settled, and that WE goes inactive before the address lines change again. The data must be stable before and after the falling edge of WE.

In practical terms, WE is usually generated by a 2X clock. If a 2X clock is not available, the falling edge of the system clock can be used. However, there are inherent risks in this approach, since the WE pulse must be guaranteed inactive before the next rising edge of the system clock. Several older application notes are available from Xilinx that discuss the design of level-sensitive RAMs.

However, the edge-triggered RAM available in the XC4000 Series is superior to level-sensitive RAM for almost every application.



Figure 9: 16x2 (or 16x1) Level-Sensitive Single-Port RAM

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Figure 10: 32x1 Level-Sensitive Single-Port RAM (F and G addresses are identical)



Figure 14: Detail of XC4000E Dedicated Carry Logic

Input/Output Blocks (IOBs)

User-configurable input/output blocks (IOBs) provide the interface between external package pins and the internal logic. Each IOB controls one package pin and can be configured for input, output, or bidirectional signals.

Figure 15 shows a simplified block diagram of the XC4000E IOB. A more complete diagram which includes the boundary scan logic of the XC4000E IOB can be found in Figure 40 on page 43, in the “Boundary Scan” section.

The XC4000X IOB contains some special features not included in the XC4000E IOB. These features are highlighted in a simplified block diagram found in **Figure 16**, and discussed throughout this section. When XC4000X special features are discussed, they are clearly identified in the text. Any feature not so identified is present in both XC4000E and XC4000X devices.

I/O Input Signals

Two paths, labeled I1 and I2 in [Figure 15](#) and [Figure 16](#), bring input signals into the array. Inputs also connect to an input register that can be programmed as either an edge-triggered flip-flop or a level-sensitive latch.

The choice is made by placing the appropriate library symbol. For example, IFD is the basic input flip-flop (rising edge triggered), and ILD is the basic input latch (transparent-High). Variations with inverted clocks are available, and some combinations of latches and flip-flops can be implemented in a single IOB, as described in the *XACT Libraries Guide*.

The XC4000E inputs can be globally configured for either TTL (1.2V) or 5.0 volt CMOS thresholds, using an option in the bitstream generation software. There is a slight input hysteresis of about 300mV. The XC4000E output levels are also configurable; the two global adjustments of input threshold and output level are independent.

Inputs on the XC4000XL are TTL compatible and 3.3V CMOS compatible. Outputs on the XC4000XL are pulled to the 3.3V positive supply.

The inputs of XC4000 Series 5-Volt devices can be driven by the outputs of any 3.3-Volt device, if the 5-Volt inputs are in TTL mode.

Supported sources for XC4000 Series device inputs are shown in [Table 8](#).

Any XC4000 Series 5-Volt device with its outputs configured in TTL mode can drive the inputs of any typical 3.3-Volt device. (For a detailed discussion of how to interface between 5 V and 3.3 V devices, see the 3V Products section of *The Programmable Logic Data Book*.)

Supported destinations for XC4000 Series device outputs are shown in [Table 12](#).

An output can be configured as open-drain (open-collector) by placing an OBUFT symbol in a schematic or HDL code, then tying the 3-state pin (T) to the output signal, and the input pin (I) to Ground. (See [Figure 18](#).)

Table 12: Supported Destinations for XC4000 Series Outputs

Destination	XC4000 Series Outputs		
	3.3 V, CMOS	5 V, TTL	5 V, CMOS
Any typical device, Vcc = 3.3 V, CMOS-threshold inputs	✓	✓	some ¹
Any device, Vcc = 5 V, TTL-threshold inputs	✓	✓	✓
Any device, Vcc = 5 V, CMOS-threshold inputs	Unreliable Data		✓

1. Only if destination device has 5-V tolerant inputs

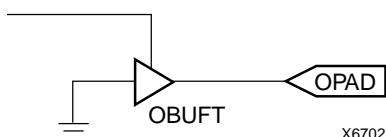


Figure 18: Open-Drain Output

Output Slew Rate

The slew rate of each output buffer is, by default, reduced, to minimize power bus transients when switching non-critical signals. For critical signals, attach a FAST attribute or property to the output buffer or flip-flop.

For XC4000E devices, maximum total capacitive load for simultaneous fast mode switching in the same direction is 200 pF for all package pins between each Power/Ground pin pair. For XC4000X devices, additional internal

Power/Ground pin pairs are connected to special Power and Ground planes within the packages, to reduce ground bounce. Therefore, the maximum total capacitive load is 300 pF between each external Power/Ground pin pair. Maximum loading may vary for the low-voltage devices.

For slew-rate limited outputs this total is two times larger for each device type: 400 pF for XC4000E devices and 600 pF for XC4000X devices. This maximum capacitive load should not be exceeded, as it can result in ground bounce of greater than 1.5 V amplitude and more than 5 ns duration. This level of ground bounce may cause undesired transient behavior on an output, or in the internal logic. This restriction is common to all high-speed digital ICs, and is not particular to Xilinx or the XC4000 Series.

XC4000 Series devices have a feature called “Soft Start-up,” designed to reduce ground bounce when all outputs are turned on simultaneously at the end of configuration. When the configuration process is finished and the device starts up, the first activation of the outputs is automatically slew-rate limited. Immediately following the initial activation of the I/O, the slew rate of the individual outputs is determined by the individual configuration option for each IOB.

Global Three-State

A separate Global 3-State line (not shown in [Figure 15](#) or [Figure 16](#)) forces all FPGA outputs to the high-impedance state, unless boundary scan is enabled and is executing an EXTEST instruction. This global net (GTS) does not compete with other routing resources; it uses a dedicated distribution network.

GTS can be driven from any user-programmable pin as a global 3-state input. To use this global net, place an input pad and input buffer in the schematic or HDL code, driving the GTS pin of the STARTUP symbol. A specific pin location can be assigned to this input using a LOC attribute or property, just as with any other user-programmable pad. An inverter can optionally be inserted after the input buffer to invert the sense of the Global 3-State signal. Using GTS is similar to GSR. See [Figure 2 on page 11](#) for details.

Alternatively, GTS can be driven from any internal node.

or clear on reset and after configuration. Other than the global GSR net, no user-controlled set/reset signal is available to the I/O flip-flops. The choice of set or clear applies to both the initial state of the flip-flop and the response to the Global Set/Reset pulse. See [“Global Set/Reset” on page 11](#) for a description of how to use GSR.

JTAG Support

Embedded logic attached to the IOBs contains test structures compatible with IEEE Standard 1149.1 for boundary scan testing, permitting easy chip and board-level testing. More information is provided in [“Boundary Scan” on page 42](#).

Three-State Buffers

A pair of 3-state buffers is associated with each CLB in the array. (See [Figure 27 on page 30](#).) These 3-state buffers can be used to drive signals onto the nearest horizontal longlines above and below the CLB. They can therefore be used to implement multiplexed or bidirectional buses on the horizontal longlines, saving logic resources. Programmable pull-up resistors attached to these longlines help to implement a wide wired-AND function.

The buffer enable is an active-High 3-state (i.e. an active-Low enable), as shown in [Table 13](#).

Another 3-state buffer with similar access is located near each I/O block along the right and left edges of the array. (See [Figure 33 on page 34](#).)

The horizontal longlines driven by the 3-state buffers have a weak keeper at each end. This circuit prevents undefined floating levels. However, it is overridden by any driver, even a pull-up resistor.

Special longlines running along the perimeter of the array can be used to wire-AND signals coming from nearby IOBs or from internal longlines. These longlines form the wide edge decoders discussed in [“Wide Edge Decoders” on page 27](#).

Three-State Buffer Modes

The 3-state buffers can be configured in three modes:

- Standard 3-state buffer
- Wired-AND with input on the I pin
- Wired OR-AND

Standard 3-State Buffer

All three pins are used. Place the library element BUFT. Connect the input to the I pin and the output to the O pin. The T pin is an active-High 3-state (i.e. an active-Low enable). Tie the T pin to Ground to implement a standard buffer.

Wired-AND with Input on the I Pin

The buffer can be used as a Wired-AND. Use the WAND1 library symbol, which is essentially an open-drain buffer. WAND4, WAND8, and WAND16 are also available. See the *XACT Libraries Guide* for further information.

The T pin is internally tied to the I pin. Connect the input to the I pin and the output to the O pin. Connect the outputs of all the WAND1s together and attach a PULLUP symbol.

Wired OR-AND

The buffer can be configured as a Wired OR-AND. A High level on either input turns off the output. Use the WOR2AND library symbol, which is essentially an open-drain 2-input OR gate. The two input pins are functionally equivalent. Attach the two inputs to the I0 and I1 pins and tie the output to the O pin. Tie the outputs of all the WOR2ANDs together and attach a PULLUP symbol.

Three-State Buffer Examples

[Figure 21](#) shows how to use the 3-state buffers to implement a wired-AND function. When all the buffer inputs are High, the pull-up resistor(s) provide the High output.

[Figure 22](#) shows how to use the 3-state buffers to implement a multiplexer. The selection is accomplished by the buffer 3-state signal.

Pay particular attention to the polarity of the T pin when using these buffers in a design. Active-High 3-state (T) is identical to an active-Low output enable, as shown in [Table 13](#).

Table 13: Three-State Buffer Functionality

IN	T	OUT
X	1	Z
IN	0	IN



Figure 21: Open-Drain Buffers Implement a Wired-AND Function

circuit prevents undefined floating levels. However, it is overridden by any driver, even a pull-up resistor.

Each XC4000E longline has a programmable splitter switch at its center, as does each XC4000X longline driven by TBUFs. This switch can separate the line into two independent routing channels, each running half the width or height of the array.

Each XC4000X longline not driven by TBUFs has a buffered programmable splitter switch at the 1/4, 1/2, and 3/4 points of the array. Due to the buffering, XC4000X longline performance does not deteriorate with the larger array sizes. If the longline is split, the resulting partial longlines are independent.

Routing connectivity of the longlines is shown in [Figure 27 on page 30](#).

Direct Interconnect (XC4000X only)

The XC4000X offers two direct, efficient and fast connections between adjacent CLBs. These nets facilitate a data flow from the left to the right side of the device, or from the top to the bottom, as shown in [Figure 30](#). Signals routed on the direct interconnect exhibit minimum interconnect propagation delay and use no general routing resources.

The direct interconnect is also present between CLBs and adjacent IOBs. Each IOB on the left and top device edges has a direct path to the nearest CLB. Each CLB on the right and bottom edges of the array has a direct path to the nearest two IOBs, since there are two IOBs for each row or column of CLBs.

The place and route software uses direct interconnect whenever possible, to maximize routing resources and minimize interconnect delays.



Figure 30: XC4000X Direct Interconnect

I/O Routing

XC4000 Series devices have additional routing around the IOB ring. This routing is called a VersaRing. The VersaRing facilitates pin-swapping and redesign without affecting board layout. Included are eight double-length lines spanning two CLBs (four IOBs), and four longlines. Global lines and Wide Edge Decoder lines are provided. XC4000X devices also include eight octal lines.

A high-level diagram of the VersaRing is shown in [Figure 31](#). The shaded arrows represent routing present only in XC4000X devices.

[Figure 33 on page 34](#) is a detailed diagram of the XC4000E and XC4000X VersaRing. The area shown includes two IOBs. There are two IOBs per CLB row or column, therefore this diagram corresponds to the CLB routing diagram shown in [Figure 27 on page 30](#). The shaded areas represent routing and routing connections present only in XC4000X devices.

Octal I/O Routing (XC4000X only)

Between the XC4000X CLB array and the pad ring, eight interconnect tracks provide for versatility in pin assignment and fixed pinout flexibility. (See [Figure 32 on page 33](#).)

These routing tracks are called octals, because they can be broken every eight CLBs (sixteen IOBs) by a programmable buffer that also functions as a splitter switch. The buffers are staggered, so each line goes through a buffer at every eighth CLB location around the device edge.

The octal lines bend around the corners of the device. The lines cross at the corners in such a way that the segment most recently buffered before the turn has the farthest distance to travel before the next buffer, as shown in [Figure 32](#).

Table 16: Pin Descriptions (Continued)

Pin Name	I/O During Config.	I/O After Config.	Pin Description
$\overline{CS0}$, CS1, \overline{WS} , \overline{RS}	I	I/O	These four inputs are used in Asynchronous Peripheral mode. The chip is selected when $\overline{CS0}$ is Low and CS1 is High. While the chip is selected, a Low on Write Strobe (\overline{WS}) loads the data present on the D0 - D7 inputs into the internal data buffer. A Low on Read Strobe (\overline{RS}) changes D7 into a status output — High if Ready, Low if Busy — and drives D0 - D6 High. In Express mode, CS1 is used as a serial-enable signal for daisy-chaining. \overline{WS} and \overline{RS} should be mutually exclusive, but if both are Low simultaneously, the Write Strobe overrides. After configuration, these are user-programmable I/O pins.
A0 - A17	O	I/O	During Master Parallel configuration, these 18 output pins address the configuration EPROM. After configuration, they are user-programmable I/O pins.
A18 - A21 (XC4003XL to XC4085XL)	O	I/O	During Master Parallel configuration with an XC4000X master, these 4 output pins add 4 more bits to address the configuration EPROM. After configuration, they are user-programmable I/O pins. (See Master Parallel Configuration section for additional details.)
D0 - D7	I	I/O	During Master Parallel and Peripheral configuration, these eight input pins receive configuration data. After configuration, they are user-programmable I/O pins.
DIN	I	I/O	During Slave Serial or Master Serial configuration, DIN is the serial configuration data input receiving data on the rising edge of CCLK. During Parallel configuration, DIN is the D0 input. After configuration, DIN is a user-programmable I/O pin.
DOUT	O	I/O	During configuration in any mode but Express mode, DOUT is the serial configuration data output that can drive the DIN of daisy-chained slave FPGAs. DOUT data changes on the falling edge of CCLK, one-and-a-half CCLK periods after it was received at the DIN input. In Express mode for XC4000E and XC4000X only, DOUT is the status output that can drive the CS1 of daisy-chained FPGAs, to enable and disable downstream devices. After configuration, DOUT is a user-programmable I/O pin.
Unrestricted User-Programmable I/O Pins			
I/O	Weak Pull-up	I/O	These pins can be configured to be input and/or output after configuration is completed. Before configuration is completed, these pins have an internal high-value pull-up resistor (25 k Ω - 100 k Ω) that defines the logic level as High.

Boundary Scan

The 'bed of nails' has been the traditional method of testing electronic assemblies. This approach has become less appropriate, due to closer pin spacing and more sophisticated assembly methods like surface-mount technology and multi-layer boards. The IEEE Boundary Scan Standard 1149.1 was developed to facilitate board-level testing of electronic assemblies. Design and test engineers can imbed a standard test logic structure in their device to achieve high fault coverage for I/O and internal logic. This structure is easily implemented with a four-pin interface on any boundary scan-compatible IC. IEEE 1149.1-compatible devices may be serial daisy-chained together, connected in parallel, or a combination of the two.

The XC4000 Series implements IEEE 1149.1-compatible BYPASS, PRELOAD/SAMPLE and EXTEST boundary scan instructions. When the boundary scan configuration option is selected, three normal user I/O pins become dedicated inputs for these functions. Another user output pin becomes the dedicated boundary scan output. The details

of how to enable this circuitry are covered later in this section.

By exercising these input signals, the user can serially load commands and data into these devices to control the driving of their outputs and to examine their inputs. This method is an improvement over bed-of-nails testing. It avoids the need to over-drive device outputs, and it reduces the user interface to four pins. An optional fifth pin, a reset for the control logic, is described in the standard but is not implemented in Xilinx devices.

The dedicated on-chip logic implementing the IEEE 1149.1 functions includes a 16-state machine, an instruction register and a number of data registers. The functional details can be found in the IEEE 1149.1 specification and are also discussed in the Xilinx application note XAPP 017: "*Boundary Scan in XC4000 Devices*."

Figure 40 on page 43 shows a simplified block diagram of the XC4000E Input/Output Block with boundary scan implemented. XC4000X boundary scan logic is identical.

Figure 41 on page 44 is a diagram of the XC4000 Series boundary scan logic. It includes three bits of Data Register per IOB, the IEEE 1149.1 Test Access Port controller, and the Instruction Register with decodes.

XC4000 Series devices can also be configured through the boundary scan logic. See "Readback" on page 55.

Data Registers

The primary data register is the boundary scan register. For each IOB pin in the FPGA, bonded or not, it includes three bits for In, Out and 3-State Control. Non-IOB pins have appropriate partial bit population for In or Out only. PROGRAM, CCLK and DONE are not included in the boundary scan register. Each EXTEST CAPTURE-DR state captures all In, Out, and 3-state pins.

The data register also includes the following non-pin bits: TDO.T, and TDO.O, which are always bits 0 and 1 of the

data register, respectively, and BSCANT.UPD, which is always the last bit of the data register. These three boundary scan bits are special-purpose Xilinx test signals.

The other standard data register is the single flip-flop BYPASS register. It synchronizes data being passed through the FPGA to the next downstream boundary scan device.

The FPGA provides two additional data registers that can be specified using the BSCAN macro. The FPGA provides two user pins (BSCAN.SEL1 and BSCAN.SEL2) which are the decodes of two user instructions. For these instructions, two corresponding pins (BSCAN.TDO1 and BSCAN.TDO2) allow user scan data to be shifted out on TDO. The data register clock (BSCAN.DRCK) is available for control of test logic which the user may wish to implement with CLBs. The NAND of TCK and RUN-TEST-IDLE is also provided (BSCAN.IDLE).

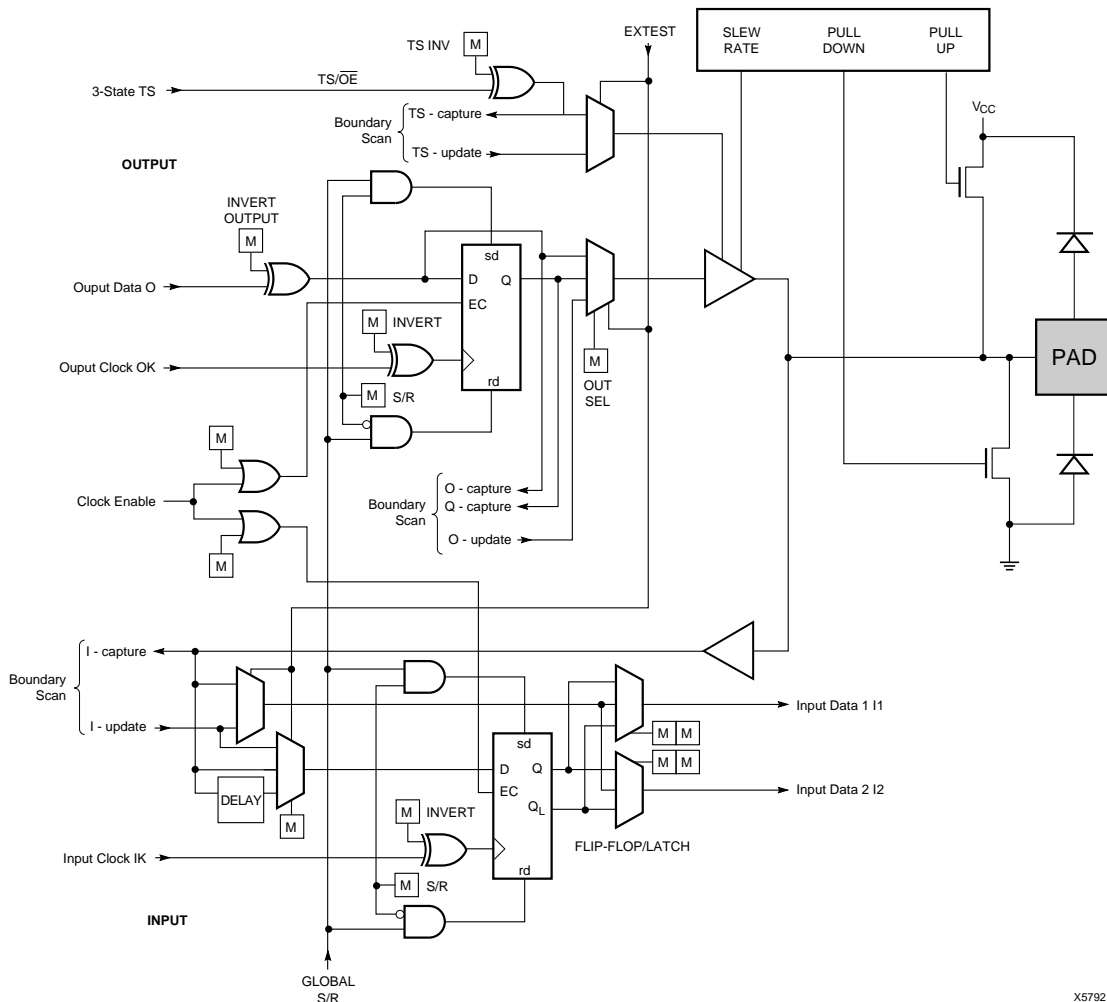
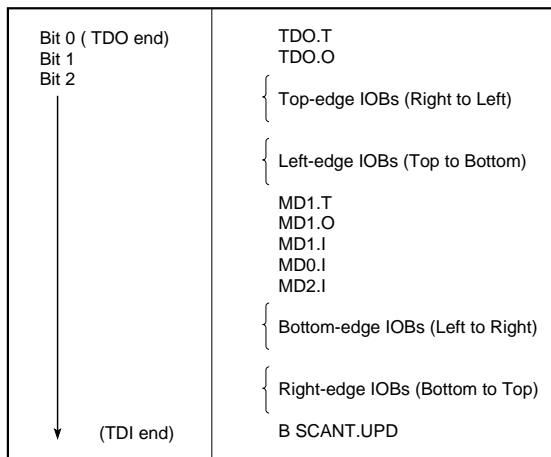


Figure 40: Block Diagram of XC4000E IOB with Boundary Scan (some details not shown). XC4000X Boundary Scan Logic is Identical.

Table 17: Boundary Scan Instructions

Instruction	I1	I2	I0	Test Selected	TDO Source	I/O Data Source
0	0	0	0	EXTEST	DR	DR
0	0	1	1	SAMPLE/PR ELOAD	DR	Pin/Logic
0	1	0	0	USER 1	BSCAN. TDO1	User Logic
0	1	1	1	USER 2	BSCAN. TDO2	User Logic
1	0	0	0	READBACK	Readback Data	Pin/Logic
1	0	1	1	CONFIGURE	DOUT	Disabled
1	1	0	0	Reserved	—	—
1	1	1	1	BYPASS	Bypass Register	—



X6075

Figure 42: Boundary Scan Bit Sequence

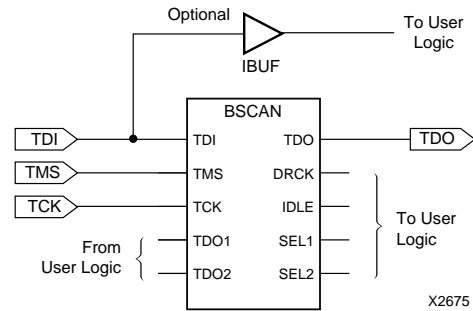
Avoiding Inadvertent Boundary Scan

If TMS or TCK is used as user I/O, care must be taken to ensure that at least one of these pins is held constant during configuration. In some applications, a situation may occur where TMS or TCK is driven during configuration. This may cause the device to go into boundary scan mode and disrupt the configuration process.

To prevent activation of boundary scan during configuration, do either of the following:

- TMS: Tie High to put the Test Access Port controller in a benign RESET state
- TCK: Tie High or Low—don't toggle this clock input.

For more information regarding boundary scan, refer to the Xilinx Application Note XAPP 017.001, "Boundary Scan in XC4000E Devices."



X2675

Figure 43: Boundary Scan Schematic Example

Configuration

Configuration is the process of loading design-specific programming data into one or more FPGAs to define the functional operation of the internal blocks and their interconnections. This is somewhat like loading the command registers of a programmable peripheral chip. XC4000 Series devices use several hundred bits of configuration data per CLB and its associated interconnects. Each configuration bit defines the state of a static memory cell that controls either a function look-up table bit, a multiplexer input, or an interconnect pass transistor. The XACT^{step} development system translates the design into a netlist file. It automatically partitions, places and routes the logic and generates the configuration data in PROM format.

Special Purpose Pins

Three configuration mode pins (M2, M1, M0) are sampled prior to configuration to determine the configuration mode. After configuration, these pins can be used as auxiliary connections. M2 and M0 can be used as inputs, and M1 can be used as an output. The XACT^{step} development system does not use these resources unless they are explicitly specified in the design entry. This is done by placing a special pad symbol called MD2, MD1, or MD0 instead of the input or output pad symbol.

In XC4000 Series devices, the mode pins have weak pull-up resistors during configuration. With all three mode pins High, Slave Serial mode is selected, which is the most popular configuration mode. Therefore, for the most common configuration mode, the mode pins can be left unconnected. (Note, however, that the internal pull-up resistor value can be as high as 100 kΩ.) After configuration, these pins can individually have weak pull-up or pull-down resistors, as specified in the design. A pull-down resistor value of 4.7 kΩ is recommended.

These pins are located in the lower left chip corner and are near the readback nets. This location allows convenient routing if compatibility with the XC2000 and XC3000 family conventions of M0/RT, M1/RD is desired.

Start-up from a User Clock (STARTUP.CLK)

When, instead of CCLK, a user-supplied start-up clock is selected, Q1 is used to bridge the unknown phase relationship between CCLK and the user clock. This arbitration causes an unavoidable one-cycle uncertainty in the timing of the rest of the start-up sequence.

DONE Goes High to Signal End of Configuration

XC4000 Series devices read the expected length count from the bitstream and store it in an internal register. The length count varies according to the number of devices and the composition of the daisy chain. Each device also counts the number of CCLKs during configuration.

Two conditions have to be met in order for the DONE pin to go high:

- the chip's internal memory must be full, and
- the configuration length count must be met, *exactly*.

This is important because the counter that determines when the length count is met begins with the very first CCLK, not the first one after the preamble.

Therefore, if a stray bit is inserted before the preamble, or the data source is not ready at the time of the first CCLK, the internal counter that holds the number of CCLKs will be one ahead of the actual number of data bits read. At the end of configuration, the configuration memory will be full, but the number of bits in the internal counter will not match the expected length count.

As a consequence, a Master mode device will continue to send out CCLKs until the internal counter turns over to zero, and then reaches the correct length count a second time. This will take several seconds [$2^{24} * \text{CCLK period}$] — which is sometimes interpreted as the device not configuring at all.

If it is not possible to have the data ready at the time of the first CCLK, the problem can be avoided by increasing the number in the length count by the appropriate value. The *XACT User Guide* includes detailed information about manually altering the length count.

Note that DONE is an open-drain output and does not go High unless an internal pull-up is activated or an external pull-up is attached. The internal pull-up is activated as the default by the bitstream generation software.

Release of User I/O After DONE Goes High

By default, the user I/O are released one CCLK cycle after the DONE pin goes High. If CCLK is not clocked after DONE goes High, the outputs remain in their initial state — 3-stated, with a 50 k Ω - 100 k Ω pull-up. The delay from DONE High to active user I/O is controlled by an option to the bitstream generation software.

Release of Global Set/Reset After DONE Goes High

By default, Global Set/Reset (GSR) is released two CCLK cycles after the DONE pin goes High. If CCLK is not clocked twice after DONE goes High, all flip-flops are held in their initial set or reset state. The delay from DONE High to GSR inactive is controlled by an option to the bitstream generation software.

Configuration Complete After DONE Goes High

Three full CCLK cycles are required after the DONE pin goes High, as shown in [Figure 47 on page 53](#). If CCLK is not clocked three times after DONE goes High, readback cannot be initiated and most boundary scan instructions cannot be used.

Configuration Through the Boundary Scan Pins

XC4000 Series devices can be configured through the boundary scan pins. The basic procedure is as follows:

- Power up the FPGA with $\overline{\text{INIT}}$ held Low (or drive the $\overline{\text{PROGRAM}}$ pin Low for more than 300 ns followed by a High while holding $\overline{\text{INIT}}$ Low). Holding $\overline{\text{INIT}}$ Low allows enough time to issue the CONFIG command to the FPGA. The pin can be used as I/O after configuration if a resistor is used to hold $\overline{\text{INIT}}$ Low.
- Issue the CONFIG command to the TMS input
- Wait for $\overline{\text{INIT}}$ to go High
- Sequence the boundary scan Test Access Port to the SHIFT-DR state
- Toggle TCK to clock data into TDI pin.

The user must account for all TCK clock cycles after INIT goes High, as all of these cycles affect the Length Count compare.

For more detailed information, refer to the Xilinx application note XAPP017, “*Boundary Scan in XC4000 Devices*.” This application note also applies to XC4000E and XC4000X devices.

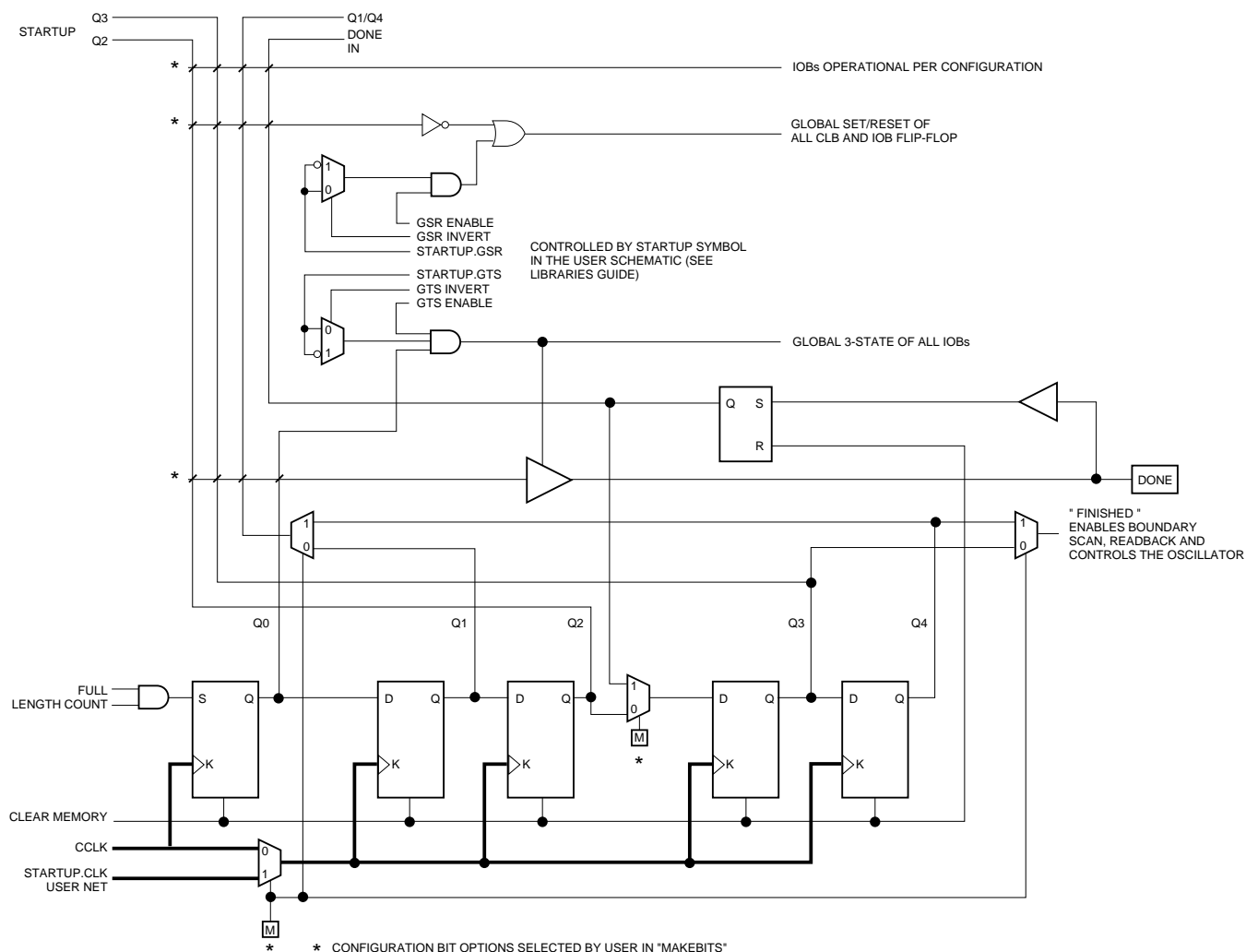


Figure 48: Start-up Logic

Readback

The user can read back the content of configuration memory and the level of certain internal nodes without interfering with the normal operation of the device.

Readback not only reports the downloaded configuration bits, but can also include the present state of the device, represented by the content of all flip-flops and latches in CLBs and IOBs, as well as the content of function generators used as RAMs.

Note that in XC4000 Series devices, configuration data is *not* inverted with respect to configuration as it is in XC2000 and XC3000 families.

XC4000 Series Readback does not use any dedicated pins, but uses four internal nets (RDBK.TRIG, RDBK.DATA, RDBK.RIP and RDBK.CLK) that can be routed to any IOB. To access the internal Readback signals, place the READ-

BACK library symbol and attach the appropriate pad symbols, as shown in [Figure 49](#).

After Readback has been initiated by a High level on RDBK.TRIG after configuration, the RDBK.RIP (Read In Progress) output goes High on the next rising edge of RDBK.CLK. Subsequent rising edges of this clock shift out Readback data on the RDBK.DATA net.

Readback data does not include the preamble, but starts with five dummy bits (all High) followed by the Start bit (Low) of the first frame. The first two data bits of the first frame are always High.

Each frame ends with four error check bits. They are read back as High. The last seven bits of the last frame are also read back as High. An additional Start bit (Low) and an 11-bit Cyclic Redundancy Check (CRC) signature follow, before RDBK.RIP returns Low.



Figure 49: Readback Schematic Example

Readback Options

Readback options are: Read Capture, Read Abort, and Clock Select. They are set with the bitstream generation software.

Read Capture

When the Read Capture option is selected, the readback data stream includes sampled values of CLB and IOB signals. The rising edge of RDBK.TRIG latches the inverted values of the four CLB outputs, the IOB output flip-flops and the input signals I1 and I2. Note that while the bits describing configuration (interconnect, function generators, and RAM content) are *not* inverted, the CLB and IOB output signals *are* inverted.

When the Read Capture option is not selected, the values of the capture bits reflect the configuration data originally written to those memory locations.

If the RAM capability of the CLBs is used, RAM data are available in readback, since they directly overwrite the F and G function-table configuration of the CLB.

RDBK.TRIG is located in the lower-left corner of the device, as shown in [Figure 50](#).

Read Abort

When the Read Abort option is selected, a High-to-Low transition on RDBK.TRIG terminates the readback operation and prepares the logic to accept another trigger.

After an aborted readback, additional clocks (up to one readback clock per configuration frame) may be required to re-initialize the control logic. The status of readback is indicated by the output control net RDBK.RIP. RDBK.RIP is High whenever a readback is in progress.

Clock Select

CCLK is the default clock. However, the user can insert another clock on RDBK.CLK. Readback control and data are clocked on rising edges of RDBK.CLK. If readback must be inhibited for security reasons, the readback control nets are simply not connected.

RDBK.CLK is located in the lower right chip corner, as shown in [Figure 50](#).

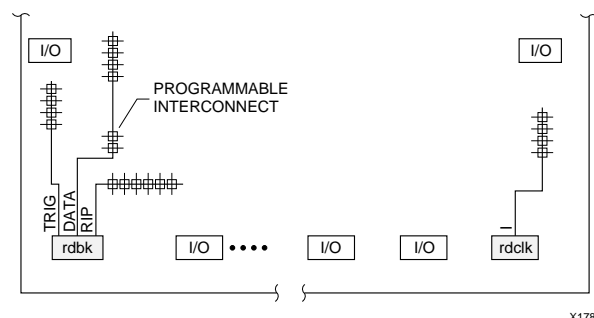


Figure 50: READBACK Symbol in Graphical Editor

Violating the Maximum High and Low Time Specification for the Readback Clock

The readback clock has a maximum High and Low time specification. In some cases, this specification cannot be met. For example, if a processor is controlling readback, an interrupt may force it to stop in the middle of a readback. This necessitates stopping the clock, and thus violating the specification.

The specification is mandatory only on clocking data at the end of a frame prior to the next start bit. The transfer mechanism will load the data to a shift register during the last six clock cycles of the frame, prior to the start bit of the following frame. This loading process is dynamic, and is the source of the maximum High and Low time requirements.

Therefore, the specification only applies to the six clock cycles prior to and including any start bit, including the clocks before the first start bit in the readback data stream. At other times, the frame data is already in the register and the register is not dynamic. Thus, it can be shifted out just like a regular shift register.

The user must precisely calculate the location of the readback data relative to the frame. The system must keep track of the position within a data frame, and disable interrupts before frame boundaries. Frame lengths and data formats are listed in [Table 19](#), [Table 20](#) and [Table 21](#).

Readback with the XChecker Cable

The XChecker Universal Download/Readback Cable and Logic Probe uses the readback feature for bitstream verification. It can also display selected internal signals on the PC or workstation screen, functioning as a low-cost in-circuit emulator.

Table 22: Pin Functions During Configuration

CONFIGURATION MODE <M2:M1:M0>						USER OPERATION
SLAVE SERIAL <1:1:1>	MASTER SERIAL <0:0:0>	SYNCH. PERIPHERAL <0:1:1>	ASYNCH. PERIPHERAL <1:0:1>	MASTER PARALLEL DOWN <1:1:0>	MASTER PARALLEL UP <1:0:0>	
M2(HIGH) (I)	M2(LOW) (I)	M2(LOW) (I)	M2(HIGH) (I)	M2(HIGH) (I)	M2(HIGH) (I)	(I)
M1(HIGH) (I)	M1(LOW) (I)	M1(HIGH) (I)	M1(LOW) (I)	M1(HIGH) (I)	M1(LOW) (I)	(O)
M0(HIGH) (I)	M0(LOW) (I)	M0(HIGH) (I)	M0(HIGH) (I)	M0(LOW) (I)	M0(LOW) (I)	(I)
HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	I/O
LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	I/O
INIT	INIT	INIT	INIT	INIT	INIT	I/O
DONE	DONE	DONE	DONE	DONE	DONE	DONE
PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM
CCLK (I)	CCLK (O)	CCLK (I)	CCLK (O)	CCLK (O)	CCLK (O)	CCLK (I)
		RDY/BUSY (O)	RDY/BUSY (O)	RCLK (O)	RCLK (O)	I/O
			RS (I)			I/O
			CS0 (I)			I/O
		DATA 7 (I)	DATA 7 (I)	DATA 7 (I)	DATA 7 (I)	I/O
		DATA 6 (I)	DATA 6 (I)	DATA 6 (I)	DATA 6 (I)	I/O
		DATA 5 (I)	DATA 5 (I)	DATA 5 (I)	DATA 5 (I)	I/O
		DATA 4 (I)	DATA 4 (I)	DATA 4 (I)	DATA 4 (I)	I/O
		DATA 3 (I)	DATA 3 (I)	DATA 3 (I)	DATA 3 (I)	I/O
		DATA 2 (I)	DATA 2 (I)	DATA 2 (I)	DATA 2 (I)	I/O
		DATA 1 (I)	DATA 1 (I)	DATA 1 (I)	DATA 1 (I)	I/O
DIN (I)	DIN (I)	DATA 0 (I)	DATA 0 (I)	DATA 0 (I)	DATA 0 (I)	I/O
DOUT	DOUT	DOUT	DOUT	DOUT	DOUT	SGCK4-GCK6-I/O
TDI	TDI	TDI	TDI	TDI	TDI	TDI-I/O
TCK	TCK	TCK	TCK	TCK	TCK	TCK-I/O
TMS	TMS	TMS	TMS	TMS	TMS	TMS-I/O
TDO	TDO	TDO	TDO	TDO	TDO	TDO-(O)
			WS (I)	A0	A0	I/O
				A1	A1	PGCK4-GCK7-I/O
			CS1	A2	A2	I/O
				A3	A3	I/O
				A4	A4	I/O
				A5	A5	I/O
				A6	A6	I/O
				A7	A7	I/O
				A8	A8	I/O
				A9	A9	I/O
				A10	A10	I/O
				A11	A11	I/O
				A12	A12	I/O
				A13	A13	I/O
				A14	A14	I/O
				A15	A15	SGCK1-GCK8-I/O
				A16	A16	PGCK1-GCK1-I/O
				A17	A17	I/O
				A18*	A18*	I/O
				A19*	A19*	I/O
				A20*	A20*	I/O
				A21*	A21*	I/O
						ALL OTHERS

Table 23: Pin Functions During Configuration

CONFIGURATION MODE <M2:M1:M0>						USER OPERATION
SLAVE SERIAL <1:1:1>	MASTER SERIAL <0:0:0>	SYNCH. PERIPHERAL <0:1:1>	ASYNCH. PERIPHERAL <1:0:1>	MASTER PARALLEL DOWN <1:1:0>	MASTER PARALLEL UP <1:0:0>	
M2(HIGH) (I)	M2(LOW) (I)	M2(LOW) (I)	M2(HIGH) (I)	M2(HIGH) (I)	M2(HIGH) (I)	(I)
M1(HIGH) (I)	M1(LOW) (I)	M1(HIGH) (I)	M1(LOW) (I)	M1(HIGH) (I)	M1(LOW) (I)	(O)
M0(HIGH) (I)	M0(LOW) (I)	M0(HIGH) (I)	M0(HIGH) (I)	M0(LOW) (I)	M0(LOW) (I)	(I)
HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	I/O
LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	I/O
INIT	INIT	INIT	INIT	INIT	INIT	I/O
DONE	DONE	DONE	DONE	DONE	DONE	DONE
PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM
CCLK (I)	CCLK (O)	CCLK (I)	CCLK (O)	CCLK (O)	CCLK (O)	CCLK (I)
		RDY/BUSY (O)	RDY/BUSY (O)	RCLK (O)	RCLK (O)	I/O
			RS (I)			I/O
			CS0 (I)			I/O
		DATA 7 (I)	DATA 7 (I)	DATA 7 (I)	DATA 7 (I)	I/O
		DATA 6 (I)	DATA 6 (I)	DATA 6 (I)	DATA 6 (I)	I/O
		DATA 5 (I)	DATA 5 (I)	DATA 5 (I)	DATA 5 (I)	I/O
		DATA 4 (I)	DATA 4 (I)	DATA 4 (I)	DATA 4 (I)	I/O
		DATA 3 (I)	DATA 3 (I)	DATA 3 (I)	DATA 3 (I)	I/O
		DATA 2 (I)	DATA 2 (I)	DATA 2 (I)	DATA 2 (I)	I/O
		DATA 1 (I)	DATA 1 (I)	DATA 1 (I)	DATA 1 (I)	I/O
DIN (I)	DIN (I)	DATA 0 (I)	DATA 0 (I)	DATA 0 (I)	DATA 0 (I)	I/O
DOUT	DOUT	DOUT	DOUT	DOUT	DOUT	SGCK4-GCK6-I/O
TDI	TDI	TDI	TDI	TDI	TDI	TDI-I/O
TCK	TCK	TCK	TCK	TCK	TCK	TCK-I/O
TMS	TMS	TMS	TMS	TMS	TMS	TMS-I/O
TDO	TDO	TDO	TDO	TDO	TDO	TDO-(O)
			WS (I)	A0	A0	I/O
				A1	A1	PGCK4-GCK7-I/O
			CS1	A2	A2	I/O
				A3	A3	I/O
				A4	A4	I/O
				A5	A5	I/O
				A6	A6	I/O
				A7	A7	I/O
				A8	A8	I/O
				A9	A9	I/O
				A10	A10	I/O
				A11	A11	I/O
				A12	A12	I/O
				A13	A13	I/O
				A14	A14	I/O
				A15	A15	SGCK1-GCK8-I/O
				A16	A16	PGCK1-GCK1-I/O
				A17	A17	I/O
				A18*	A18*	I/O
				A19*	A19*	I/O
				A20*	A20*	I/O
				A21*	A21*	I/O
						ALL OTHERS

* XC4000X only

- Notes
1. A shaded table cell represents a 50 kΩ - 100 kΩ pull-up before and during configuration.
 2. (I) represents an input; (O) represents an output.
 3. INIT is an open-drain output during configuration.

Synchronous Peripheral Mode

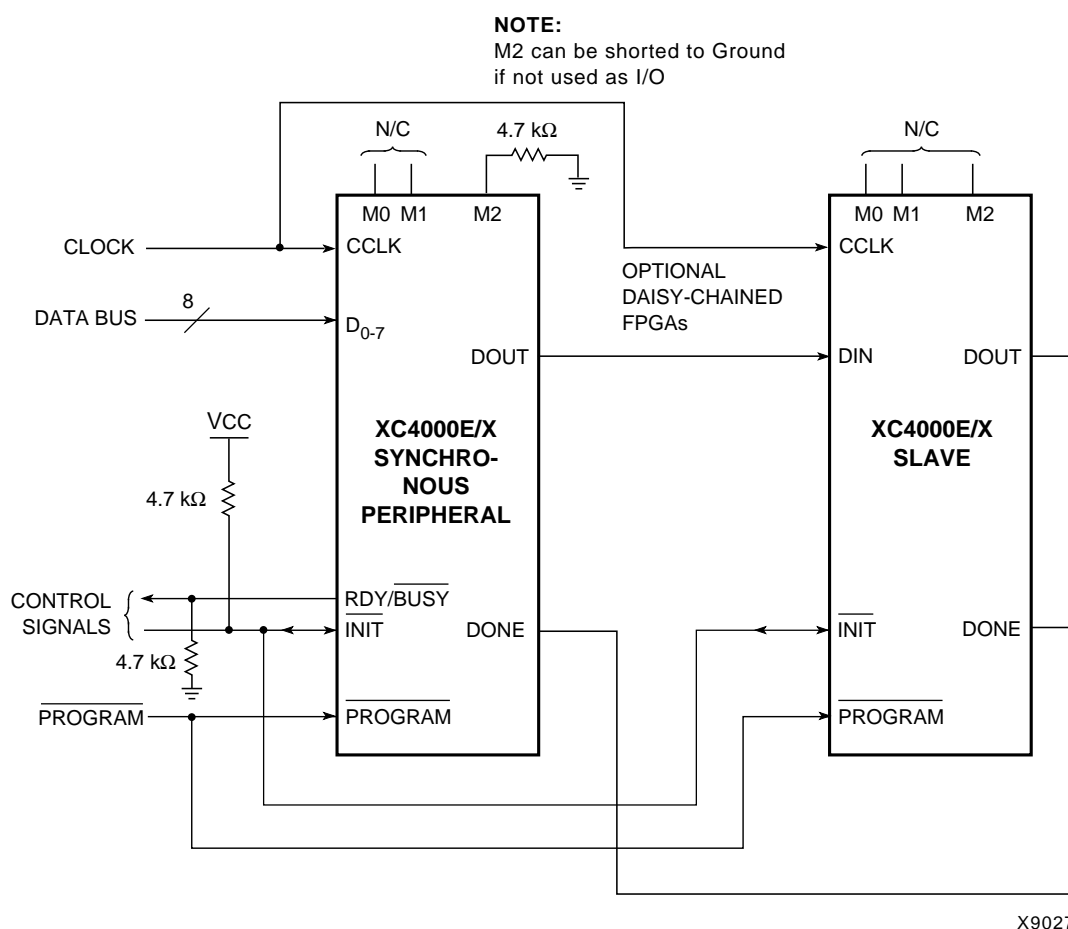
Synchronous Peripheral mode can also be considered Slave Parallel mode. An external signal drives the CCLK input(s) of the FPGA(s). The first byte of parallel configuration data must be available at the Data inputs of the lead FPGA a short setup time before the rising CCLK edge. Subsequent data bytes are clocked in on every eighth consecutive rising CCLK edge.

The same CCLK edge that accepts data, also causes the RDY/ $\overline{\text{BUSY}}$ output to go High for one CCLK period. The pin name is a misnomer. In Synchronous Peripheral mode it is really an ACKNOWLEDGE signal. Synchronous operation does not require this response, but it is a meaningful signal for test purposes. Note that RDY/ $\overline{\text{BUSY}}$ is pulled High with a high-impedance pullup prior to $\overline{\text{INIT}}$ going High.

The lead FPGA serializes the data and presents the preamble data (and all data that overflows the lead device) on its DOUT pin. There is an internal delay of 1.5 CCLK periods, which means that DOUT changes on the falling CCLK edge, and the next FPGA in the daisy chain accepts data on the subsequent rising CCLK edge.

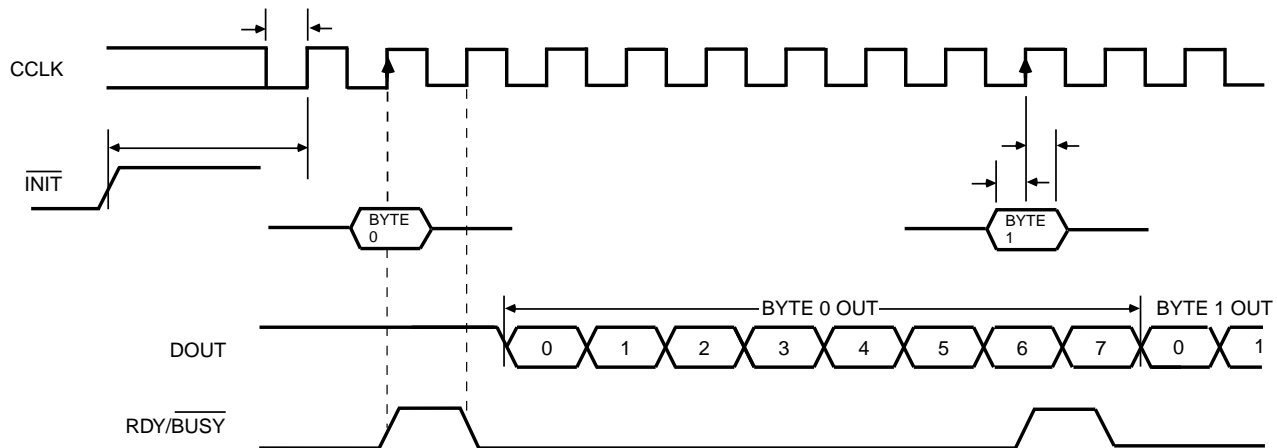
In order to complete the serial shift operation, 10 additional CCLK rising edges are required after the last data byte has been loaded, plus one more CCLK cycle for each daisy-chained device.

Synchronous Peripheral mode is selected by a <011> on the mode pins (M2, M1, M0).



X9027

Figure 56: Synchronous Peripheral Mode Circuit Diagram



X6096

	Description	Symbol	Min	Max	Units
CCLK	INIT (High) setup time	T_{IC}	5		μs
	D0 - D7 setup time	T_{DC}	60		ns
	D0 - D7 hold time	T_{CD}	0		ns
	CCLK High time	T_{CCH}	50		ns
	CCLK Low time	T_{CCL}	60		ns
	CCLK Frequency	F_{CC}		8	MHz

- Notes:
1. Peripheral Synchronous mode can be considered Slave Parallel mode. An external CCLK provides timing, clocking in the **first** data byte on the **second** rising edge of CCLK after INIT goes High. Subsequent data bytes are clocked in on every eighth consecutive rising edge of CCLK.
 2. The RDY/BUSY line goes High for one CCLK period after data has been clocked in, although synchronous operation does not require such a response.
 3. The pin name RDY/BUSY is a misnomer. In Synchronous Peripheral mode this is really an ACKNOWLEDGE signal.
 4. Note that data starts to shift out serially on the DOUT pin 0.5 CCLK periods after it was loaded in parallel. Therefore, additional CCLK pulses are clearly required after the last byte has been loaded.

Figure 57: Synchronous Peripheral Mode Programming Switching Characteristics

Asynchronous Peripheral Mode

Write to FPGA

Asynchronous Peripheral mode uses the trailing edge of the logic AND condition of \overline{WS} and $\overline{CS0}$ being Low and \overline{RS} and $\overline{CS1}$ being High to accept byte-wide data from a microprocessor bus. In the lead FPGA, this data is loaded into a double-buffered UART-like parallel-to-serial converter and is serially shifted into the internal logic.

The lead FPGA presents the preamble data (and all data that overflows the lead device) on its DOUT pin. The RDY/BUSY output from the lead FPGA acts as a handshake signal to the microprocessor. RDY/BUSY goes Low when a byte has been received, and goes High again when the byte-wide input buffer has transferred its information into the shift register, and the buffer is ready to receive new data. A new write may be started immediately, as soon as the RDY/BUSY output has gone Low, acknowledging receipt of the previous data. Write may not be terminated until RDY/BUSY is High again for one CCLK period. Note that RDY/BUSY is pulled High with a high-impedance pull-up prior to \overline{INIT} going High.

The length of the \overline{BUSY} signal depends on the activity in the UART. If the shift register was empty when the new byte was received, the \overline{BUSY} signal lasts for only two CCLK periods. If the shift register was still full when the new byte was received, the \overline{BUSY} signal can be as long as nine CCLK periods.

Note that after the last byte has been entered, only seven of its bits are shifted out. CCLK remains High with DOUT equal to bit 6 (the next-to-last bit) of the last byte entered.

The RDY/ \overline{BUSY} handshake can be ignored if the delay from any one Write to the end of the next Write is guaranteed to be longer than 10 CCLK periods.

Status Read

The logic AND condition of the $\overline{CS0}$, $\overline{CS1}$ and \overline{RS} inputs puts the device status on the Data bus.

- D7 High indicates Ready
- D7 Low indicates Busy
- D0 through D6 go unconditionally High

It is mandatory that the whole start-up sequence be started and completed by one byte-wide input. Otherwise, the pins used as Write Strobe or Chip Enable might become active outputs and interfere with the final byte transfer. If this transfer does not occur, the start-up sequence is not completed all the way to the finish (point F in [Figure 47 on page 53](#)).

In this case, at worst, the internal reset is not released. At best, Readback and Boundary Scan are inhibited. The length-count value, as generated by the XACTstep software, ensures that these problems never occur.

Although RDY/ \overline{BUSY} is brought out as a separate signal, microprocessors can more easily read this information on one of the data lines. For this purpose, D7 represents the RDY/ \overline{BUSY} status when \overline{RS} is Low, \overline{WS} is High, and the two chip select lines are both active.

Asynchronous Peripheral mode is selected by a <101> on the mode pins (M2, M1, M0).

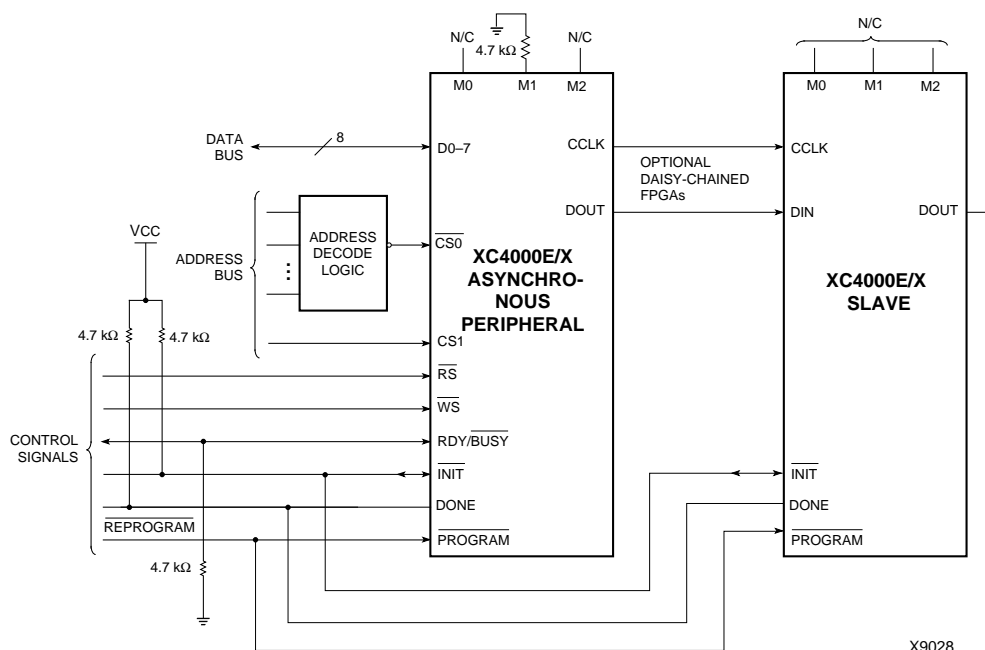


Figure 58: Asynchronous Peripheral Mode Circuit Diagram

Table 25: Component Availability Chart for XC4000E FPGAs

	PINS	TYPE	CODE	84	100	100	120	144	156	160	191	208	208	223	225	240	240	299	304
				Plast. PLCC	Plast. PQFP	Plast. VQFP	Ceram. PGA	Plast. TQFP	Ceram. PGA	Plast. PQFP	Ceram. PGA	High-Perf. QFP	Plast. PQFP	Ceram. PGA	Plast. BGA	High-Perf. QFP	Plast. PQFP	Ceram. PGA	High-Perf. QF
				PC84	PQ100	VQ100	PG120	TQ144	PG156	PQ160	PG191	HQ208	PQ208	PG223	BG225	HQ240	PQ240	PG299	HQ304
XC4003E	-4	C I	C I	C I	C I														
	-3	C I	C I	C I	C I														
	-2	C I	C I	C I	C I														
	-1	C	C	C	C														
XC4005E	-4	C I	C I					C I	C I	C I			C I						
	-3	C I	C I					C I	C I	C I			C I						
	-2	C I	C I					C I	C I	C I			C I						
	-1	C	C					C	C	C			C						
XC4006E	-4	C I						C I	C I	C I			C I						
	-3	C I						C I	C I	C I			C I						
	-2	C I						C I	C I	C I			C I						
	-1	C						C	C	C			C						
XC4008E	-4	C I								C I	C I		C I						
	-3	C I								C I	C I		C I						
	-2	C I								C I	C I		C I						
	-1	C								C	C		C						
XC4010E	-4	C I								C I	C I	C I	C I			C I			
	-3	C I								C I	C I	C I	C I			C I			
	-2	C I								C I	C I	C I	C I			C I			
	-1	C								C	C	C	C			C			
XC4013E	-4									C I		C I	C I	C I	C I	C I	C I		
	-3									C I		C I	C I	C I	C I	C I	C I		
	-2									C I		C I	C I	C I	C I	C I	C I		
	-1									C		C	C	C	C	C	C		
XC4020E	-4											C I		C I		C I			
	-3											C I		C I		C I			
	-2											C I		C I		C I			
	-1											C		C		C			
XC4025E	-4													C I		C I		C I	C I
	-3													C I		C I		C I	C I
	-2													C		C		C	C

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C = Commercial $T_J = 0^\circ$ to $+85^\circ\text{C}$

I = Industrial $T_J = -40^\circ\text{C}$ to $+100^\circ\text{C}$

Table 26: Component Availability Chart for XC4000EX FPGAs

	PINS	TYPE	CODE	208	240	299	304	352	411	432
				High-Perf. QFP	High-Perf. QFP	Ceram. PGA	High-Perf. QFP	Plast. BGA	Ceram. PGA	Plast. BGA
				HQ208	HQ240	PG299	HQ304	BG352	PG411	BG432
XC4028EX	-4	C I	C I	C I	C I	C I	C I	C I		
	-3	C I	C I	C I	C I	C I	C I	C I		
	-2	C	C	C	C	C	C	C		
XC4036EX	-4			C I	C I		C I	C I	C I	C I
	-3			C I	C I		C I	C I	C I	C I
	-2			C	C		C	C	C	C

1/29/99

C = Commercial $T_J = 0^\circ$ to $+85^\circ\text{C}$

I = Industrial $T_J = -40^\circ\text{C}$ to $+100^\circ\text{C}$